## **PNA2601M**

### Silicon NPN Phototransistor

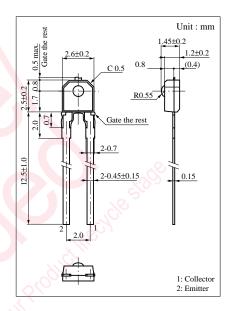
For optical control systems

#### Features

- Darlington output, high sensitivity
- Small size, thin side-view type package
- Adoption of visible light cutoff resin

#### Absolute Maximum Ratings ( $Ta = 25^{\circ}C$ )

Parameter	Symbol	Ratings	Unit	
Collector to emitter voltage	V <sub>CEO</sub>	35	V	
Emitter to collector voltage	V <sub>ECO</sub>	6	V	
Collector current	$I_{C}$	30	mA	
Collector power dissipation	P <sub>C</sub>	75	mW	
Operating ambient temperature	T <sub>opr</sub>	-25 to +65	°C ,	
Storage temperature	T <sub>stg</sub>	-30 to +85	°C	

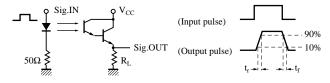


#### ■ Electro-Optical Characteristics (Ta = 25°C)

Parameter	Symbol	Conditions	min	typ	max	Unit
Dark current	$I_{CEO}$	$V_{CE} = 10V$		0.1	0.5	μΑ
Sensitivity to infrared emitters	$S_{IR}^{*1}$	$V_{CE} = 10V, H = 3.75 \mu\text{W/cm}^2$	20			μA
Peak sensitivity wavelength	$\lambda_{\mathrm{P}}$	$V_{CE} = 10V$		850		nm
Acceptance half angle	θ	Measured from the optical axis to the half power point	35			deg.
Response time	$t_r, t_f^{*2}$	$V_{CC} = 10V, I_C = 1mA, R_L = 100\Omega$		150		μs
Collector saturation voltage	V <sub>CE(sat)</sub>	$I_C = 100 \mu A, H = 3.75 \ \mu W/cm^2$		0.7	1.5	V

<sup>\*1</sup> Measurements were made using infrared light ( $\lambda = 940 \text{ nm}$ ) as a light source.

<sup>\*2</sup> Switching time measuring circuit



- t<sub>r</sub>: Rise time (Time required for the collector photo current to increase from 10% to 90% of its final value)
- $\rm t_f\colon Fall\ time\ (Time\ required\ for\ the\ collector\ photo\ current\ to$  decrease from 90% to 10% of its initial value)

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